

#### LM3414S 20V N-Channel Enhancement Mode MOSFET

#### **Features**

- 20V/5.8A,  $R_{DS(ON)}$ =25m $\Omega$ @ $V_{GS}$ =4.5V
- Super high density cell design for extremely low R<sub>DS (ON)</sub>
- Exceptional on-resistance and maximum DC current capability
- SOT-23 package design

### **Product Description**

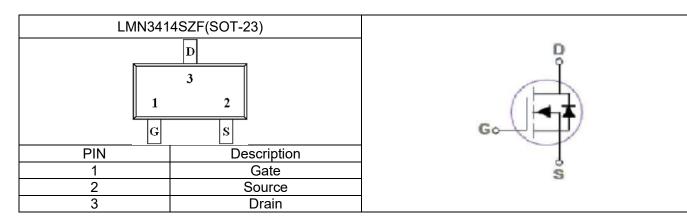
LMN3414S, N-Channel enhancement mode MOSFET, uses Advanced Trench Technology to provide excellent R<sub>DS(ON)</sub>, low gate charge.

These devices are particularly suited for low voltage power management, such as smart phone and notebook computer and other battery powered circuits, and low in-line power loss are needed in commercial industrial surface mount applications.

### **Applications**

- Portable Equipment
- Battery Powered System
- Net Working System

### **Pin Configuration**



**LMN3414S** 



### **Ordering Information**

Ordering Information						
Part Number	P/N	PKG code	Pb Free code	Package	Quantity	
LMN3414SZF	LMN3414S	Z	F	SOT-23	3000 PCS	

## **Marking Information**

Marking Information					
Part Marking	Part Marking Part Number LFC code				
14XW	14	XW			

## **Absolute Maximum Ratings**

(T<sub>C</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Parameter		Typical	Unit
V <sub>DS</sub>	Drain-Source Voltage	9		20	V
$V_{GS}$	Gate-Source Voltage	Gate-Source Voltage			V
1_	Continuous Drain Cu	Continuous Drain Current ( $T_J=150^{\circ}$ C) $\frac{T_A=25}{T_A=10}$		5.8	Α
<b>I</b> D	Continuous Diain Cu	ilelit (1J–150 C)	T <sub>A</sub> =100°C	3.7	A
I <sub>DM</sub>	Pulsed <sup>1</sup> Drain Curren			23.2	A
$P_{D}$	Power Discipation	T <sub>A</sub> =25°C		1.56	W
	Power Dissipation	T <sub>A</sub> =25°C		0.012	W/ °C
TJ	Operating Junction T	Operating Junction Temperature		-55 to +150	°C
T <sub>STG</sub>	Storage Temperature	Storage Temperature Range			°C
R <sub>0JA</sub>	Thermal Resistance-	Junction to Ambi	ent	80	°C/W

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### **Electrical Characteristics**

### (T<sub>C</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Conditions	Mi n	Тур	Max	Unit	
Static							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}$ =0V, $I_D$ =250uA	20			V	
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , ID=250Ua	0.4	0.6	0.8	V	
. ,	V <sub>GS(th)</sub> Temperature Coefficient			2		mV/ ºC	
∆BVDSS/ ∆TJ	BVDSS Temperature Coefficient	Reference to 25 °C, ID=1mA		0.02		V/ºC	
$I_{GSS}$	Gate Leakage Current	$V_{DS}$ =0V, $V_{GS}$ =±10V			±100	nA	
	Zoro Cato Voltago Drain Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V T <sub>J</sub> =25°C			1	uA	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V T <sub>J</sub> =85°C			10	uA	
		V <sub>GS</sub> =4.5V, ID=4A		20	25		
$R_{DS(on)}$	Drain-Source On-Resistance	V <sub>GS</sub> =2.5V, ID=3A		27	35	mΩ	
		V <sub>GS</sub> =1.8V, ID=2A		39	55		
<b>g</b> FS	Forward Transconductance	V <sub>DS</sub> =10V, ID=3A		6.5		S	
Dynamic							
Is	Continuous Source Current	VD=VG=DV, Force			5.8	Α	
I <sub>SM</sub>	Pulsed Source Current	Current			23.2	A	
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V, TJ=25°C			1	V	
$Q_g$	Total Gate Charge <sup>2,3</sup>	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V,		7.7	11		
$Q_gs$	Gate-Source Charge <sup>2,3</sup>	$I_D=4A$		0.9	1	nC	
$Q_gd$	Gate-Drain Charge <sup>2,3</sup>	10-4/4		2.4	5		
$C_{iss}$	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V,		535	775	pF	
Coss	Output Capacitance	f=1MHz		60	85		
$C_{rss}$	Reverse Transfer Capacitance	1-1101112		34	50		
$t_{d(on)}$	Turn-On Time <sup>2,3</sup>			4.1	8	ns	
t <sub>r</sub>	Turr-Or Time	$V_{DD}$ =10V, $R_L$ =25 $\Omega$ ,		11.6	22		
$t_{d(off)}$	Turn-Off Time <sup>2,3</sup>	I <sub>D</sub> =1A, V <sub>GS</sub> =4.5V,		23.9	45		
t <sub>f</sub>	Tuiti-Oil Tillie			7.6	14		

#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed, pulse width  $\leq$  300us, duty cycle  $\leq$  2%.
- 3. Essentially independent of operating temperature.



# **Typical Performance Characteristics**

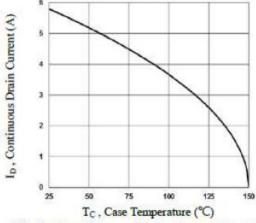


Fig.1 Continuous Drain Current vs. Tc

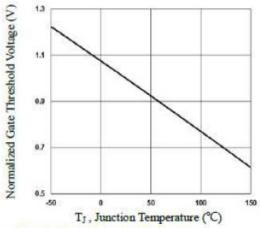


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

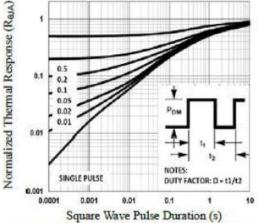


Fig.5 Normalized Transient Impedance

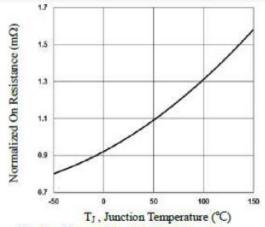


Fig.2 Normalized RDSON vs. T,

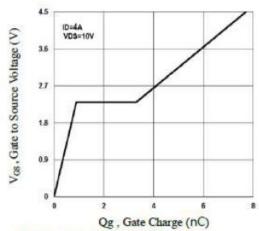


Fig.4 Gate Charge Waveform

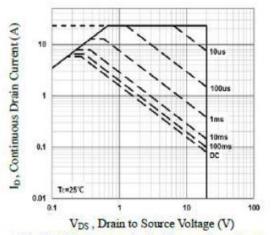
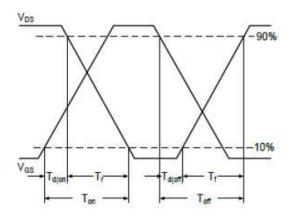


Fig.6 Maximum Safe Operation Area



## **Typical Performance Characteristics(continue)**





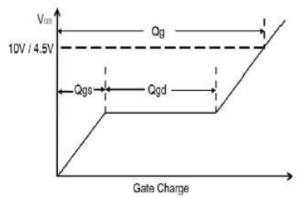
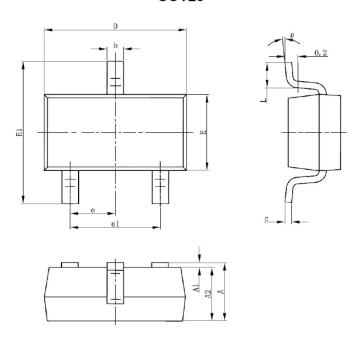


Fig.8 Gate Charge Waveform



# Package Dimension:

## SOT23



	Dimensions					
Cymphol	Millir	neters	Inches			
Symbol	Min	Max	Min	Max		
Α	0.900	1.200	0.035	0.043		
A1	0.000	0.100	0.000	0.004		
A2	0.900	1.100	0.035	0.039		
b	0.300	0.500	0.012	0.020		
С	0.080	0.150	0.003	0.006		
D	2.800	3.000	0.110	0.118		
E	1.200	1.400	0.047	0.055		
E1	2.250	2.550	0.089	0.100		
е	0.950TYP		0.037TYP			
e1	1.800	2.000	0.071	0.079		
L	0.550REF		0.022REF			
L1	0.300	0.500	0.012	0.020		
θ	0°	8°	0°	8°		



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